

**Notice of References Cited**

Application/Control No.

09/839,044

Applicant(s)/Patent Under  
Reexamination  
CORN OG ET AL.

Examiner

Ryan J. Miller

Art Unit

2621

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,477,279 B2	11-2002	Go	382/240
	B	US-2002/0159749 A1	10-2002	Kobilansky	386/1
	C	US-6,665,450 B1	12-2003	Cornog et al.	382/276
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bouthemy, P. "A Maximum Likelihood Framework for Determining Moving Edges", IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. II, May 1989, pages 499-511.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.